

<b>Notice of References Cited</b>	Application/Control No. 10/750,824		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Kim T. Huynh		Art Unit 2112	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,875,309 A	02-1999	Itkowsky et al.	710/113
*	B	US-6,434,649 B1	08-2002	Baker et al.	710/107
*	C	US-6,526,518 B1	02-2003	Catlin et al.	713/501
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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